

**FCC ID: 2ALBUVBXX**

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances  $\leq 50$  mm are determined by:

$[(\text{max. power of channel, including tune-up tolerance, mW})/(\text{min. test separation distance, mm})] \cdot [\sqrt{f(\text{GHz})}] \leq 3.0$  for 1-g SAR and  $\leq 7.5$  for 10-g extremity SAR, where:

- $f(\text{GHz})$  is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is  $< 5$  mm, a distance of 5 mm is applied to determine SAR test exclusion.

BT:

Modulation	Channel Freq. (GHz)	Conduct ed power (dBm)	Conducte d power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	1g SAR Exclusion threshold	SAR test exclusion
GFSK	2.402	-4.64	0.344	-5 $\pm$ 1	-4	0.398	<5	0.12340	3.00	YES
	2.441	-5.21	0.301	-5 $\pm$ 1	-4	0.398	<5	0.12440	3.00	YES
	2.480	-5.41	0.288	-5 $\pm$ 1	-4	0.398	<5	0.12539	3.00	YES
$\pi/4$ -DQPSK	2.402	-4.74	0.336	-5 $\pm$ 1	-4	0.398	<5	0.12340	3.00	YES
	2.441	-5.16	0.305	-5 $\pm$ 1	-4	0.398	<5	0.12440	3.00	YES
	2.480	-5.56	0.278	-5 $\pm$ 1	-4	0.398	<5	0.12539	3.00	YES
8DPSK	2.402	-4.7	0.339	-5 $\pm$ 1	-4	0.398	<5	0.12340	3.00	YES
	2.441	-5.12	0.308	-5 $\pm$ 1	-4	0.398	<5	0.12440	3.00	YES
	2.480	-5.54	0.279	-5 $\pm$ 1	-4	0.398	<5	0.12539	3.00	YES

**Conclusion:**

For the max result :  $0.12539 \leq 3.0$  for 1-g SAR, No SAR is required.

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**Signature:**

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